



MPN3404



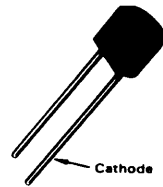
SILICON PIN SWITCHING DIODE

SILICON PIN DIODE

... designed primarily for VHF band switching applications but also suitable for use in general-purpose switching and attenuator circuits. Supplied in a cost effective TO-92 type plastic package for economical, high-volume consumer and industrial requirements.

- Rugged PIN Structure Coupled with Wirebond Construction for Optimum Reliability
- Low Series Resistance @ 100 MHz –
 $R_S = 0.7 \text{ Ohms (Typ) @ } I_F = 10 \text{ mA dc}$
- Sturdy TO-92 Style Package for Handling Ease

7.0

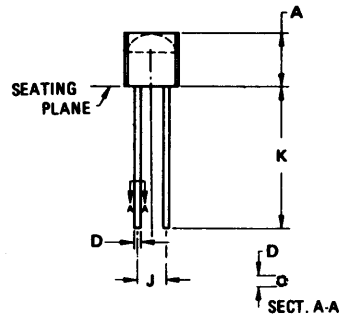


MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Reverse Voltage	V_R	20	Volts
Forward Power Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_F	400 4.0	mW mW/ $^\circ\text{C}$
Junction Temperature	T_J	+125	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-65 to +150	$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Reverse Breakdown Voltage ($I_R = 10 \mu\text{A}$)	$V_{(BR)R}$	20	–	–	Volts
Diode Capacitance (Note 1) ($V_R = 15 \text{ Vdc}$, $f = 1.0 \text{ MHz}$)	C_T	–	1.3	2.0	pF
Series Resistance (Figure 5) ($I_F = 10 \text{ mA}$)	R_S	–	0.7	0.85	Ohms
Reverse Leakage Current ($V_R = 15 \text{ Vdc}$)	I_R	–	–	0.1	μA
Series Inductance (Note 2) ($f = 250 \text{ MHz}$, Lead Length $\approx 1/16''$)	L_S	–	6.0	–	nH
Case Capacitance ($f = 1.0 \text{ MHz}$, Lead Length $\approx 1/16''$)	C_C	–	0.18	–	pF



STYLE 1:
PIN 1, ANODE
2, CATHODE

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.46	4.70	0.175	0.186
D	0.41	0.48	0.016	0.019
J	2.29	2.79	0.090	0.110
K	12.70	–	0.500	–

CASE 182-03

NOTES

- C_T is measured using a capacitance bridge (Boonton Electronics Model 75A or equivalent).
- L_S is measured on a package having a short instead of a die, using an impedance bridge (Boonton Radio Model 250A RX Meter).

TYPICAL ELECTRICAL CHARACTERISTICS

FIGURE 1 – SERIES RESISTANCE

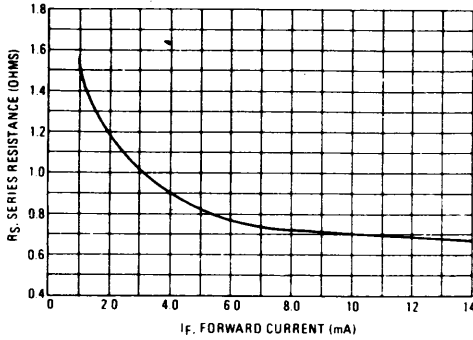


FIGURE 2 – FORWARD VOLTAGE

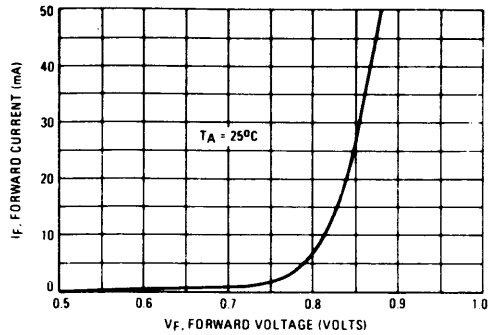


FIGURE 3 – DIODE CAPACITANCE

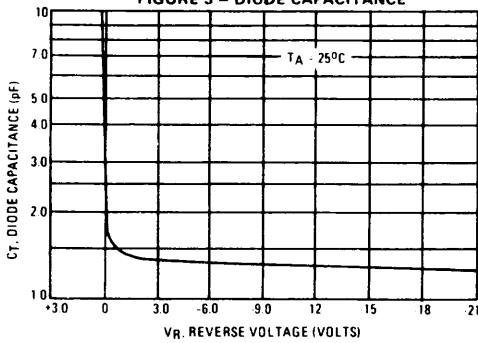


FIGURE 4 – LEAKAGE CURRENT

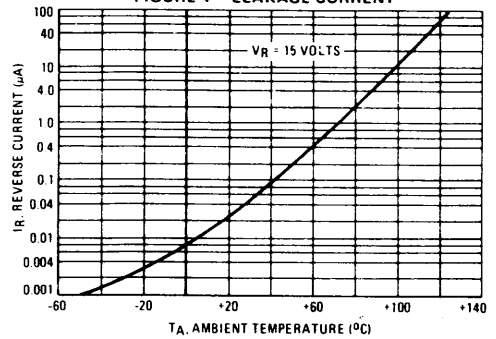
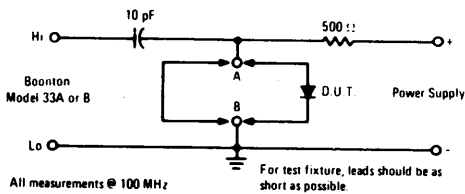


FIGURE 5 – FORWARD SERIES RESISTANCE TEST METHOD



To measure series resistance, a 10 pF capacitor is used to reduce the forward capacitance of the circuit and to prevent shorting of the external power supply through the bridge. The small signal from the bridge is prevented from shorting through the power supply by the 500-ohm resistor. The resistance of the 10 pF capacitor can be considered negligible for this measurement.

1. The RF Admittance Bridge (Boonton 33A or B) must be initially balanced, with the test circuit connected to the bridge test terminals. The conductance scale will be set at zero and the capacitance scale will be set at 120 pF, as required when using the 100 MHz test coil.

2. Use a short length of wire to short the test circuit from point "A" to "B". Then connect the power supply providing 10 mA of bias current to the test circuit.
3. Adjust the capacitance scale arm of the bridge and the "G" zero control for a minimum null on the "null meter". The null occurs at approximately 130 pF.
4. Replace the wire short with the device to be tested. Bias the device to a forward conductance state of 10 mA.
5. Obtain a minimum null on the "null meter", with the capacitance and conductance scale adjustment arms.
6. Read conductance (G) direct from the scale. Now read the capacitance value from the scale (≈ 130 pF) and subtract 120 pF which yields capacitance (C). The forward resistance (R_S) can now be calculated from:

$$R_S = \frac{2.533 G}{C^2}$$

Where:
 G – in micromhos,
 C – in pF,
 R_S – in ohms

MOTOROLA SEMICONDUCTOR TECHNICAL DATA



HIGH VOLTAGE SILICON PIN DIODES

... designed primarily for VHF band switching applications but also suitable for use in general-purpose switching and attenuator circuits. Supplied in a cost effective plastic package for economical, high-volume consumer and industrial requirements.

- Long Reverse Recovery Time
 $t_{rr} = 300$ ns (Typ)
- Rugged PIN Structure Coupled with Wirebond Construction for Optimum Reliability
- Low Series Resistance @ 100 MHz —
 $R_S = 0.7$ Ohms (Typ) @ $I_F = 10$ mAdc
- Reverse Breakdown Voltage = 200 V (Min)

MAXIMUM RATINGS

Rating	Symbol	MPN3700		MMBV3700L	Unit
		Value			
Reverse Voltage	V_R	200			Volts
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_D	280	200		mW
Junction Temperature	T_J	+125			$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55 to +150			$^\circ\text{C}$

DEVICE MARKING

MMBV3700L = 4R

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Reverse Breakdown Voltage ($I_R = 10 \mu\text{A}$)	$V_{(BR)R}$	200	—	—	Volts
Diode Capacitance ($V_R = 20$ Vdc, $f = 1.0$ MHz)	C_T	—	—	1.0	pF
Series Resistance (Figure 5) ($I_F = 10$ mA)	R_S	—	0.7	1.0	Ohms
Reverse Leakage Current ($V_R = 150$ Vdc)	I_R	—	—	0.1	μA
Reverse Recovery Time ($I_F = I_R = 10$ mA)	t_{rr}	—	300	—	ns

MMBV3700L MPN3700

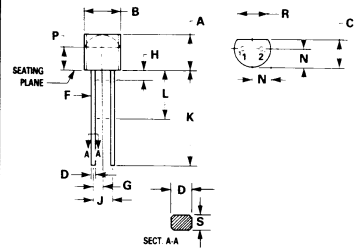
SILICON PIN SWITCHING DIODES



CASE 182-02
TO-226AC
TO-92
MPN3700



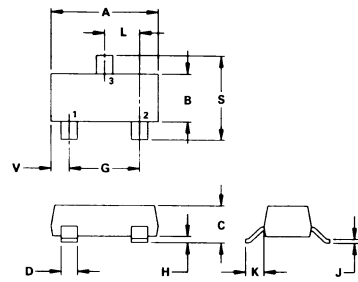
CASE 318-07
TO-236AB
SOT-23
MMBV3700L



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.32	5.33	0.170	0.210
B	4.45	5.21	0.175	0.205
C	3.18	4.19	0.125	0.165
D	0.41	0.56	0.016	0.022
F	0.407	0.482	0.016	0.019
G	1.27 BSC	—	0.050 BSC	—
H	—	1.27	—	0.050
J	2.54 BSC	—	0.100 BSC	—
K	12.70	—	0.500	—
L	6.35	—	0.250	—
N	2.03	2.66	0.080	0.105
P	2.93	—	0.115	—
R	3.43	—	0.135	—
S	0.36	0.41	0.014	0.016

STYLE 1:
PIN 1 ANODE
2 CATHODE

CASE 182-02
TO-226AC (TO-92)



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.80	3.04	0.1102	0.1197
B	1.20	1.40	0.0472	0.0551
C	0.89	1.11	0.0350	0.0440
D	0.37	0.50	0.0150	0.0200
G	1.78	2.04	0.0701	0.0807
H	0.013	0.100	0.0005	0.0040
J	0.085	0.177	0.0034	0.0070
K	0.45	0.60	0.0180	0.0236
L	0.89	1.02	0.0350	0.0401
S	2.10	2.50	0.0830	0.0984
V	0.45	0.60	0.0177	0.0236

STYLE 8:
PIN 1 ANODE
2. NO CONNECTION
3. CATHODE

CASE 318-07
TO-236AB
SOT-23

MMBV3700L, MPN3700

TYPICAL ELECTRICAL CHARACTERISTICS

FIGURE 1 — SERIES RESISTANCE

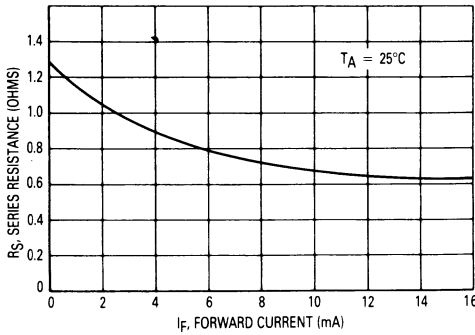


FIGURE 2 — FORWARD VOLTAGE

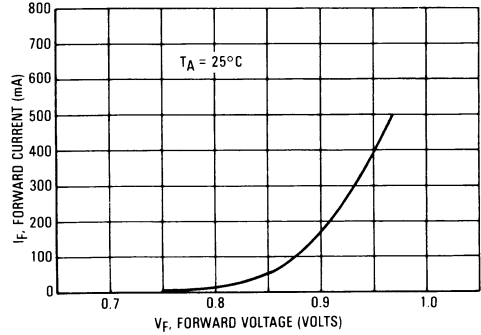


FIGURE 3 — DIODE CAPACITANCE

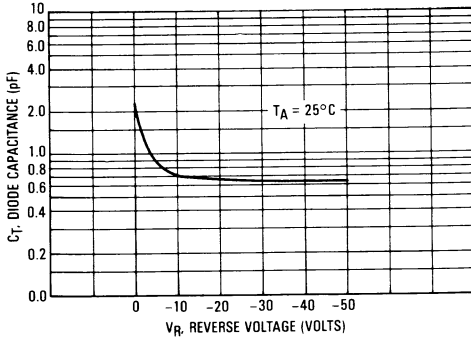


FIGURE 4 — LEAKAGE CURRENT

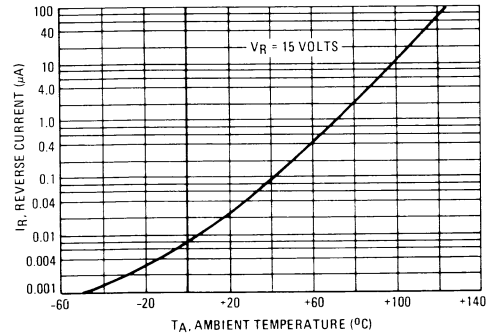
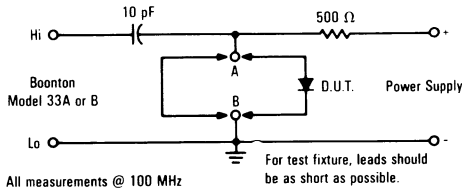


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